

IN THE CLAIMS

Please amend the claims as follows:

1. (AMENDED) An apparatus coupled to a low speed tester and a device having a first speed faster than a second speed of said low speed tester, wherein said apparatus is configured to allow said low speed tester to perform high speed tests of said device at said first speed.

2. The apparatus according to claim 1, wherein said low speed tester is further configured to control high-speed transmit, reception and verification of said device.

3. The apparatus according to claim 1, wherein said device comprises a Universal Serial Bus (USB) device.

4. The apparatus according to claim 1, further comprising:

a host emulator configured to interface said device; and
a test vector generator.

5. The apparatus according to claim 4, wherein said low speed tester is configured to control said host emulator.

6. The apparatus according to claim 4, wherein said low speed tester is configured in response to one or more test vectors.

7. The apparatus according to claim 6, wherein said test vector generator is configured to generate said one or more test vectors.

8. The apparatus according to claim 1, wherein said apparatus is further configured to test a reception and transmission operation of said device.

9. The apparatus according to claim 1, wherein said apparatus is further configured to initiate one or more test packets.

10. The apparatus according to claim 9, wherein said device is further configured to receive and verify said one or more test packets.

11. The apparatus according to claim 10, wherein said device is further configured to transmit said one or more test packets.

Count
A 6

12. (AMENDED) The apparatus according to claim 4, wherein said apparatus is further configured to receive and verify one or more transmitted test packets.

13. The apparatus according to claim 1, wherein said low speed tester is further configured to generate a pass/fail signal.

14. The apparatus according to claim 1, wherein said apparatus is configured to perform at least one test of a plurality of test modes wherein said plurality of test modes comprise USB 2.0 defined test modes for use in a production test environment.

15. (AMENDED) An apparatus comprising:

means for testing a device having a first speed; and

means for configuring a low speed tester having a second speed slower than said first speed to perform high speed tests of said device at said first speed through said testing means.

16. (AMENDED) A method for testing comprising the steps of:

(A) testing a device having a first speed with a host emulator; and

(B) configuring a low speed tester having a second speed slower than said first speed to perform high speed tests of said device at said first speed through said host emulator.

17. The method according to claim 16, wherein said device under test comprises an USB device.

18. (AMENDED) The method according to claim 16, wherein step (B) further comprises:

configuring said low speed tester to control said host emulator.

19. The method according to claim 18, wherein step (B) further comprises:

allowing said host emulator to interface with said device under test.

20. The method according to claim 16, further comprising performing at least one of a plurality of test modes wherein the plurality of test modes comprise USB 2.0 defined test modes for use in a production test environment.